

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10811071	FENNEY ET AL.
	Examiner	Art Unit
	Hajnik, Daniel F	2628

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
Update Search conducted in EAST	10/12/08	DFH
EAST text search (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB -- see search history printout)	10/12/08	DFH
Update search conducted in EAST	7/29/09	DFH
NPL search conducted in ACM, IEEE, and Google, search terms include sample, micropolygon, and primitive	7/30/09	DFH
EAST search history attached	8/1/09	DFH

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/DANIEL F HAJNIK/
Examiner.Art Unit 2628